



US00D420927S

# United States Patent [19]

Yano

[11] Patent Number: Des. 420,927  
[45] Date of Patent: \*\* Feb. 22, 2000

## [54] IC TEST-HEAD STAND

[75] Inventor: Takayuki Yano, Tokyo, Japan

[73] Assignee: Advantest Corporation, Tokyo, Japan

[\*\*] Term: 14 Years

[21] Appl. No.: 29/098,530

[22] Filed: Dec. 30, 1998

[51] LOC (7) Cl. .... 10-04

[52] U.S. Cl. .... D10/80; D34/12

[58] Field of Search ..... D10/80, 108; D34/12,  
D34/17; 37/265, 434, 285; 280/47.24; 294/54.5,  
55

## [56] References Cited

### U.S. PATENT DOCUMENTS

D. 286,698 11/1986 Spicer ..... D34/12 X  
D. 383,582 9/1997 Sinclair, Jr. .... D34/12 X

Primary Examiner—Antoine Duval Davis

Attorney, Agent, or Firm—Birch, Stewart, Kolasch & Birch, LLP

## [57] CLAIM

The ornamental design for an IC test-head stand, as shown and described.

## DESCRIPTION

FIG. 1 is a perspective view of an IC test-head stand according to a first embodiment of the present design.

FIG. 2 is a front view of the IC test-head stand shown in FIG. 1. A rear view of the IC test-head stand is omitted from the drawing since the rear view is symmetrical with the front view.

FIG. 3 is a left side view of the IC test-head stand shown in FIG. 1.

FIG. 4 is a right side view of the IC test-head stand shown in FIG. 1.

FIG. 5 is a top plan view of the IC test-head stand shown in FIG. 1.

FIG. 6 is a bottom plan view of the IC test-head stand shown in FIG. 1.

FIG. 7 is a perspective view of an IC test-head stand according to a second embodiment of the present design.

FIG. 8 is a front view of the IC test-head stand shown in FIG. 7. A rear view of the IC test-head stand is omitted from the drawing since the rear view is symmetrical with the front view.

FIG. 9 is a left side view of the IC test-head stand shown in FIG. 7.

FIG. 10 is a right side view of the IC test-head stand shown in FIG. 7.

FIG. 11 is a top plan view of the IC test-head stand shown in FIG. 7.

FIG. 12 is a bottom plan view of the IC test-head stand shown in FIG. 7.

FIG. 13 is a perspective view of an IC test-head stand according to a third embodiment of the present design.

FIG. 14 is a front view of the IC test-head stand shown in FIG. 13. A rear view of the IC test-head stand is omitted from the drawing since the rear view is symmetrical with the front view.

FIG. 15 is a left side view of the IC test-head stand shown in FIG. 13.

FIG. 16 is a right side view of the IC test-head stand shown in FIG. 13.

FIG. 17 is a top plan view of the IC test-head stand shown in FIG. 13.

FIG. 18 is a bottom plan view of the IC test-head stand shown in FIG. 13; and,

FIG. 19 is a front view of the IC test-head stand shown in FIG. 1, for illustrating the use of the IC test-head stand.

The broken line showing is for illustrative purposes only and forms no part of the claimed design.

1 Claim, 10 Drawing Sheets

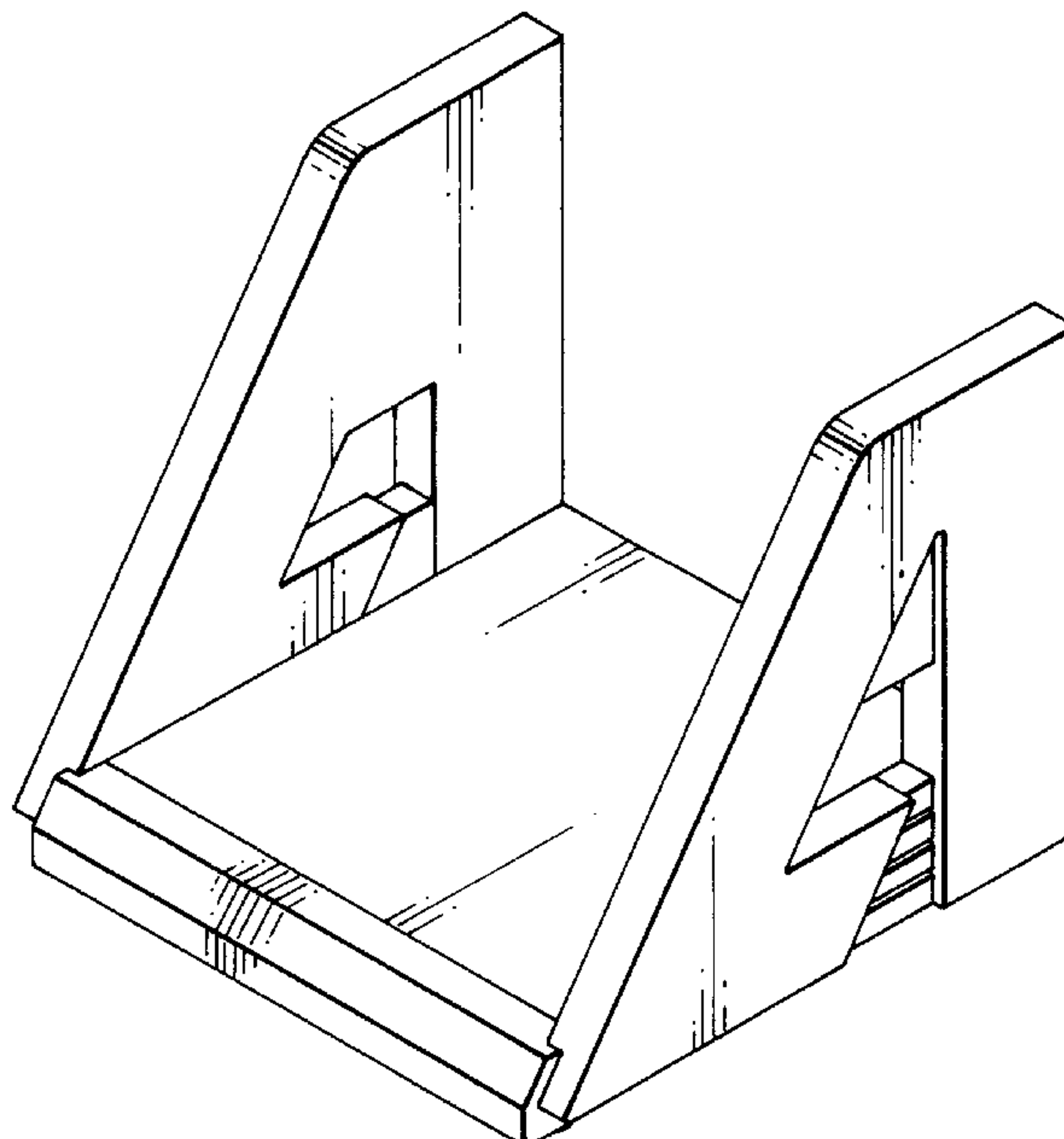


FIG. 1

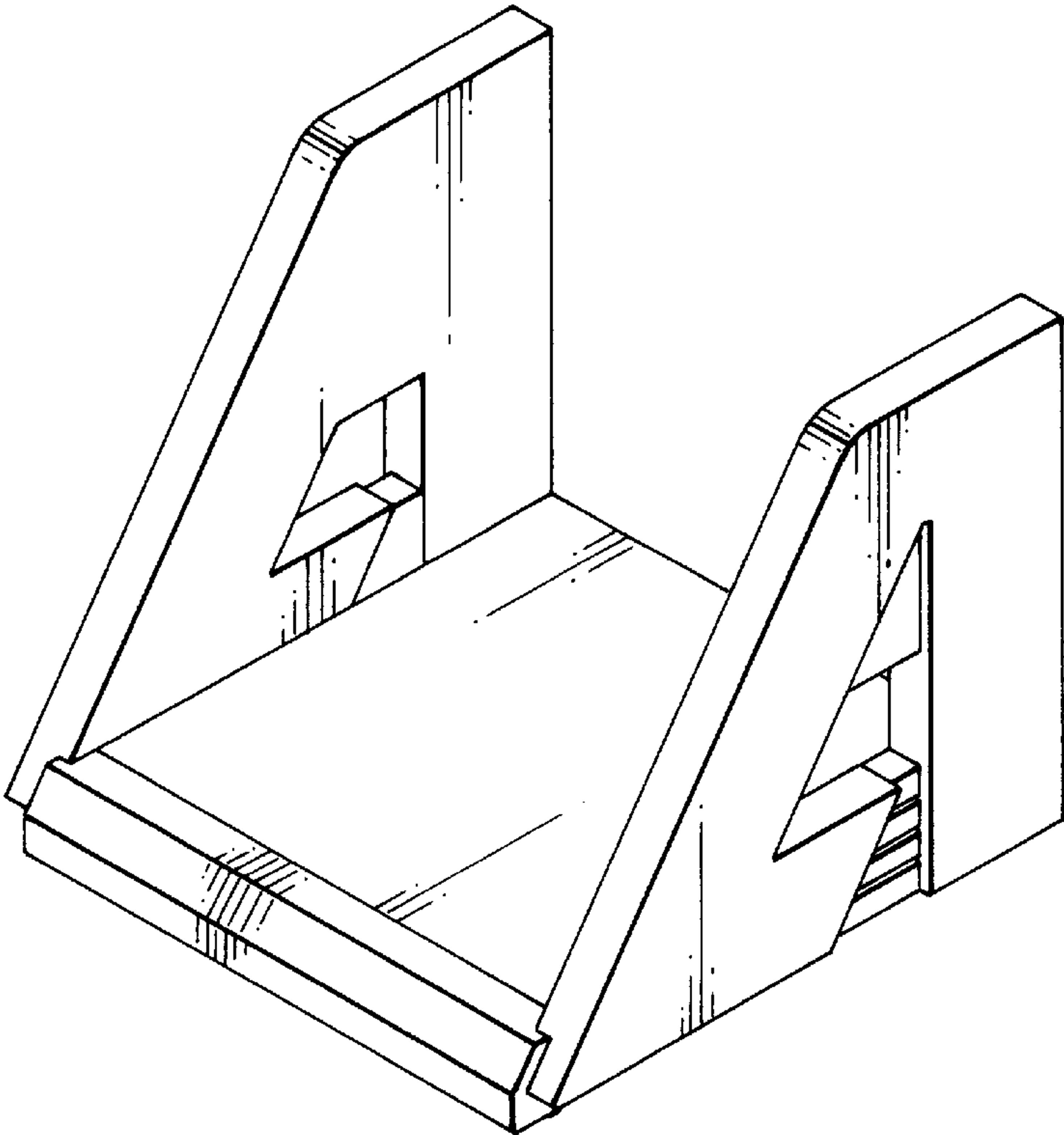


FIG. 2

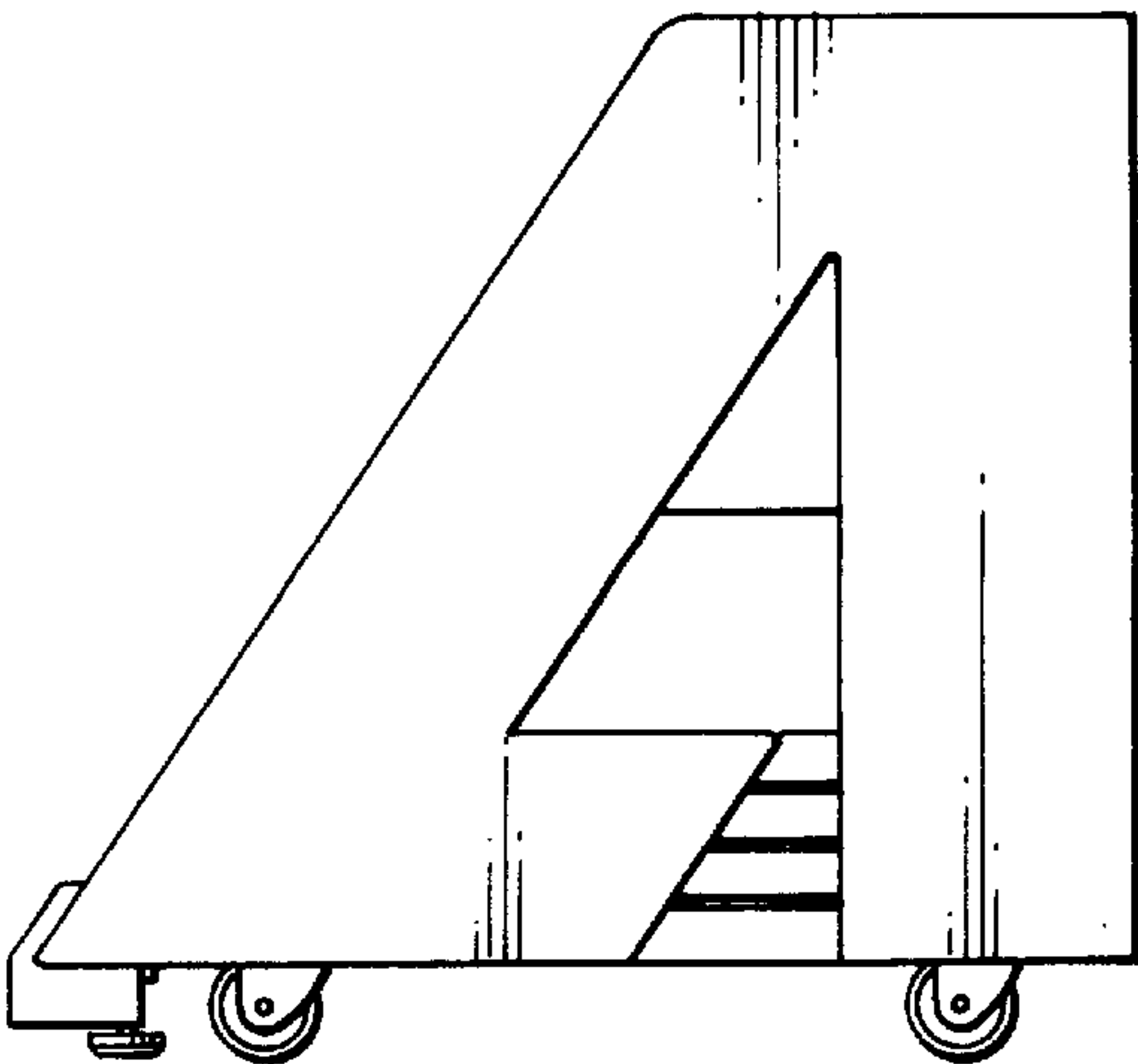


FIG. 3

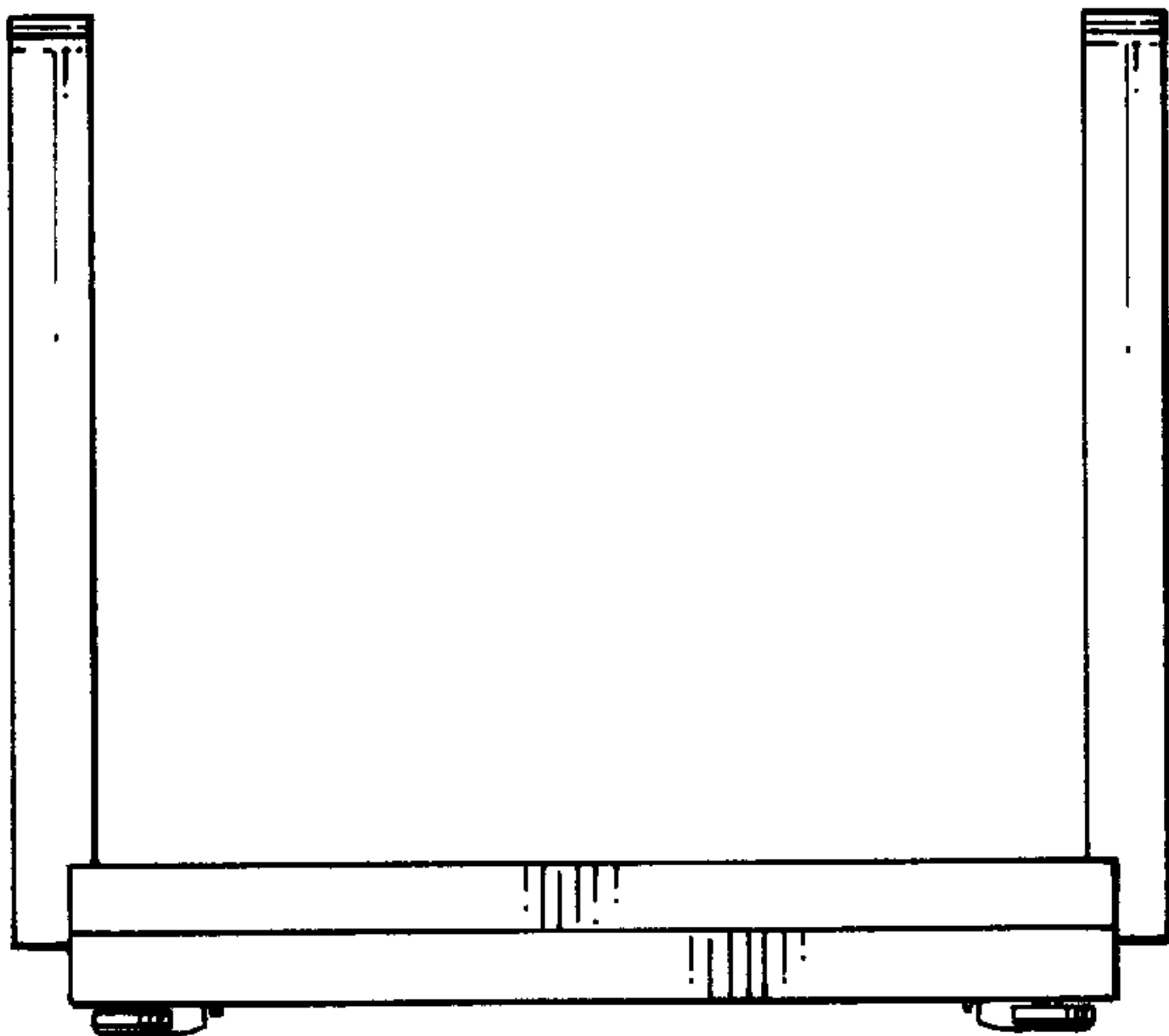


FIG. 4

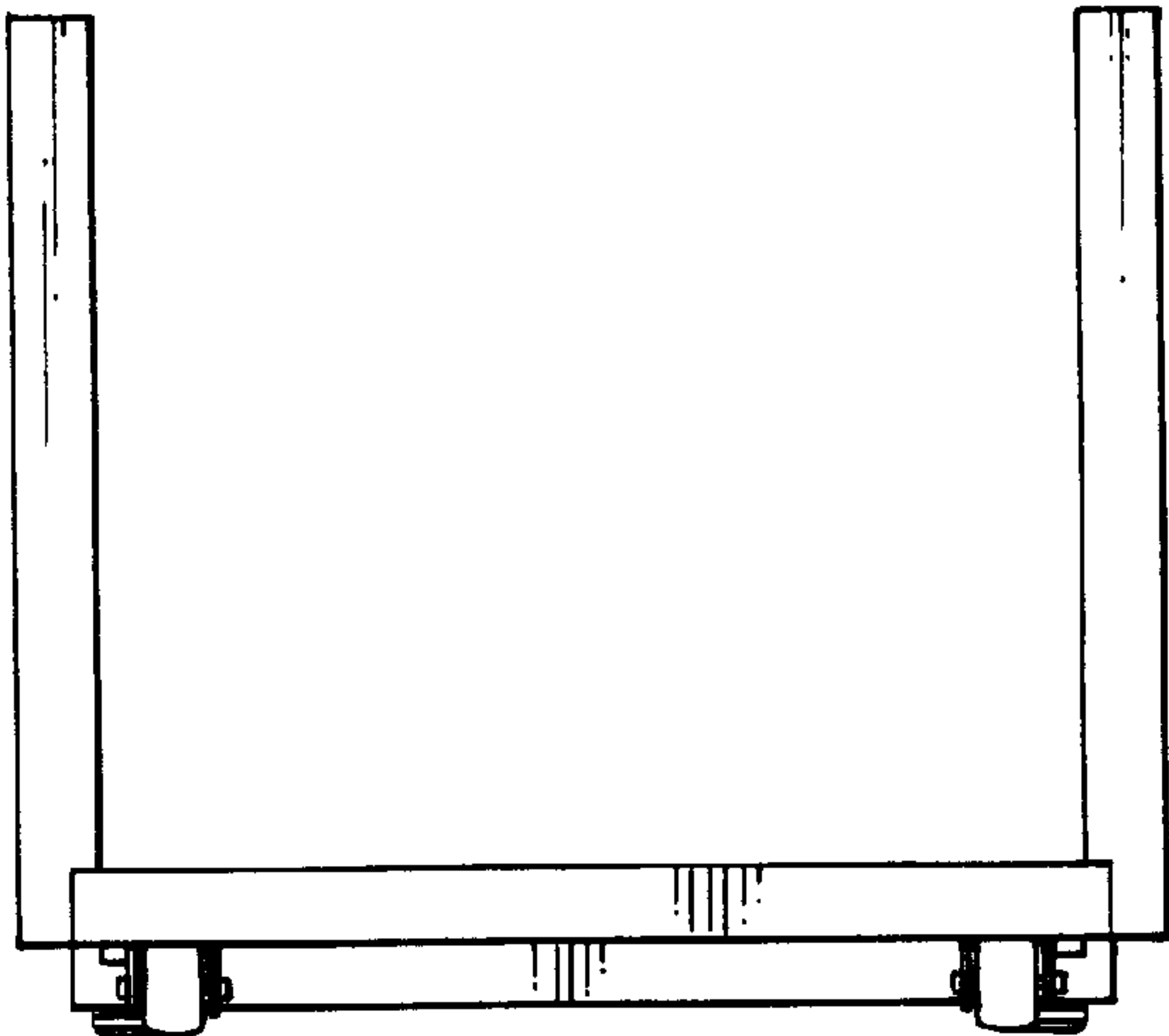


FIG. 5

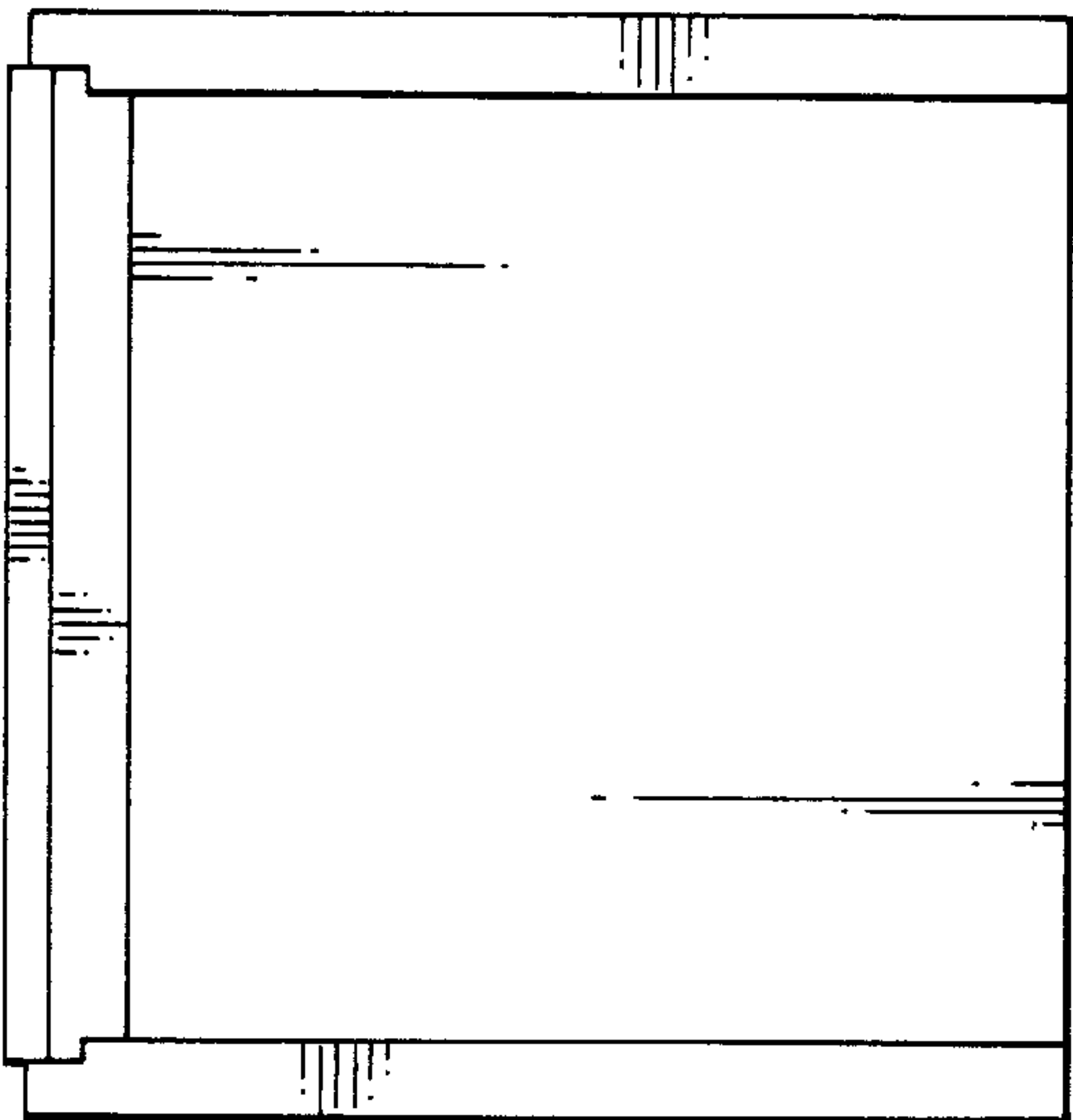


FIG. 6

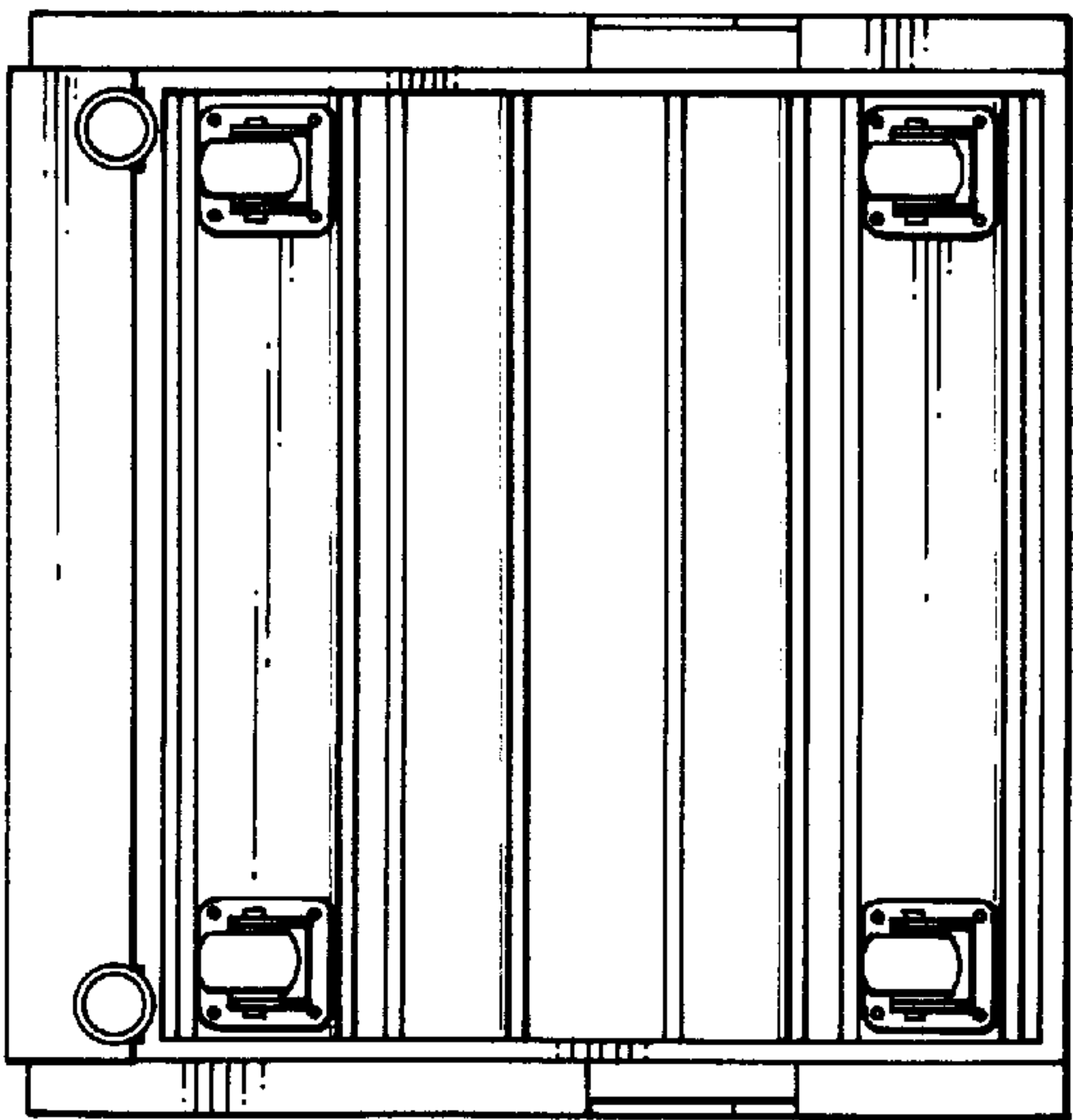


FIG. 7

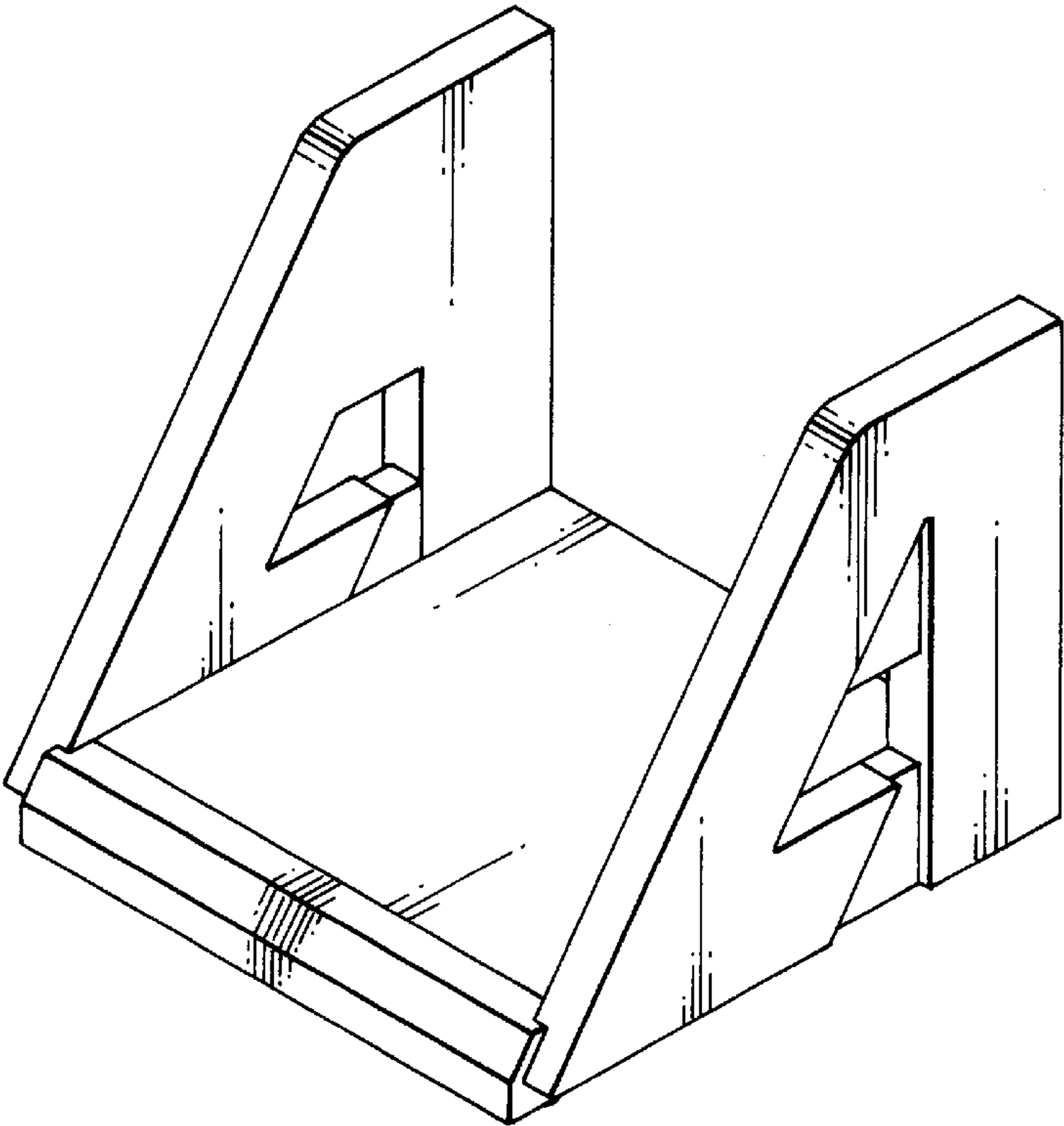


FIG. 8

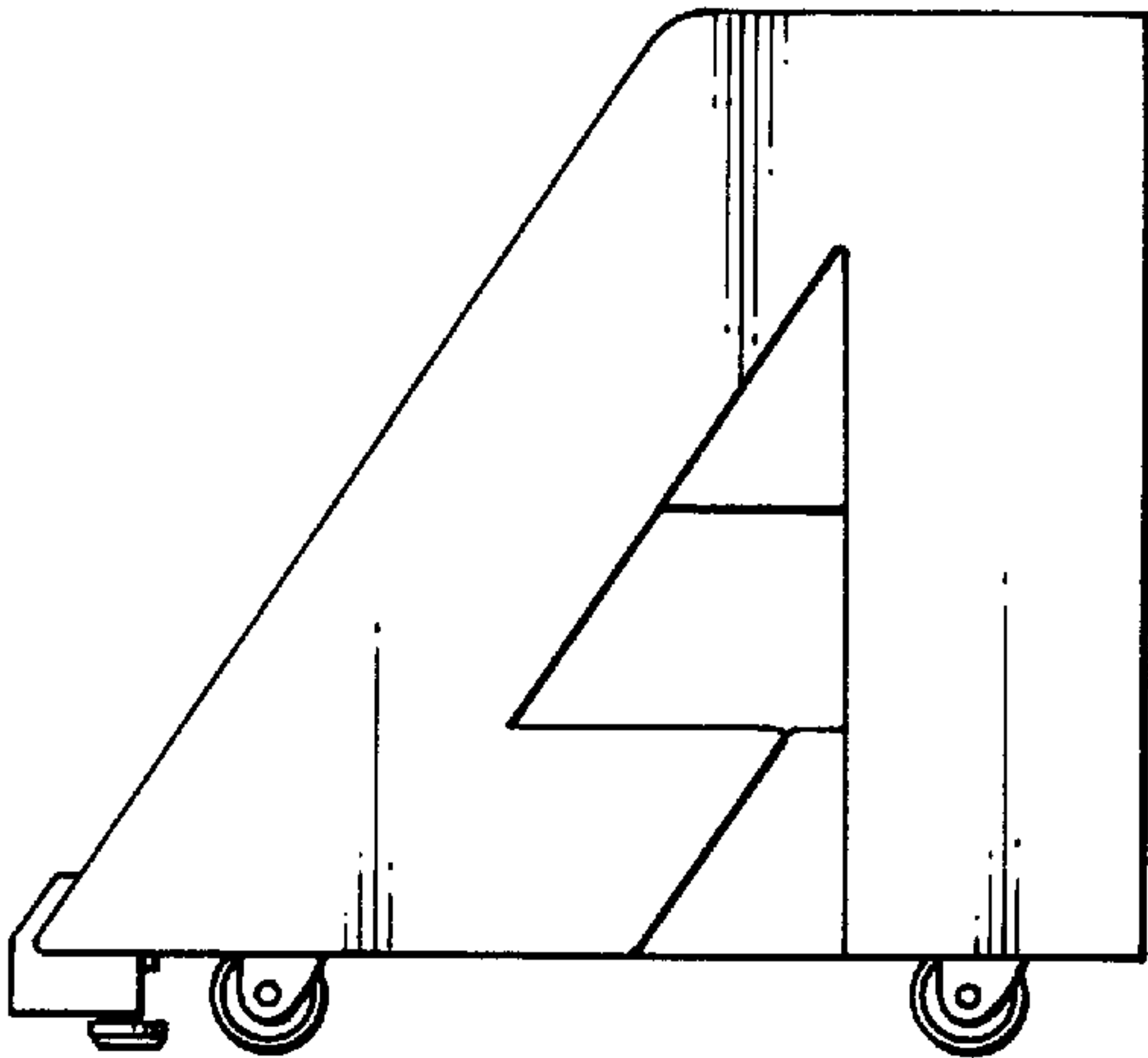


FIG. 9

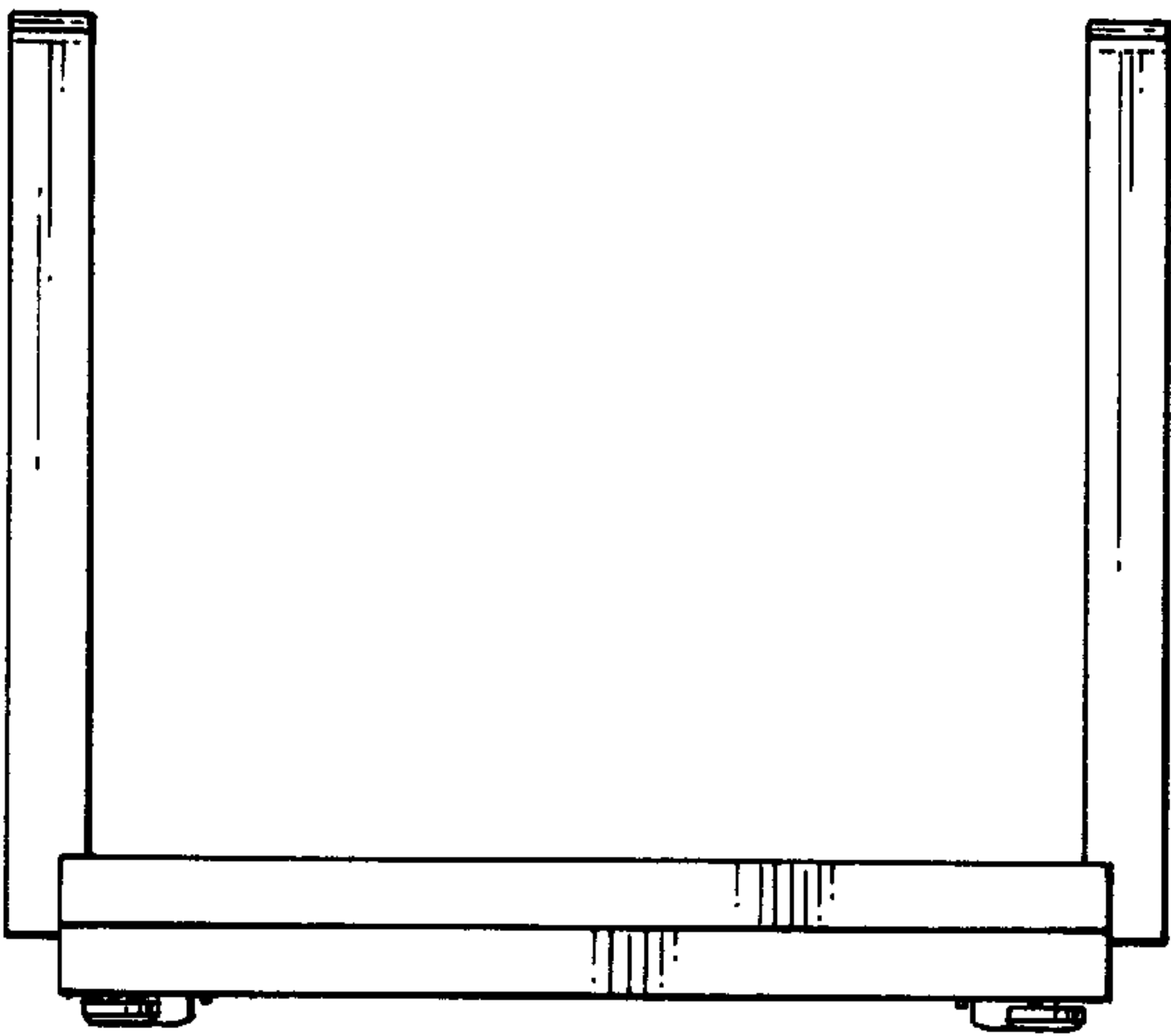


FIG. 10

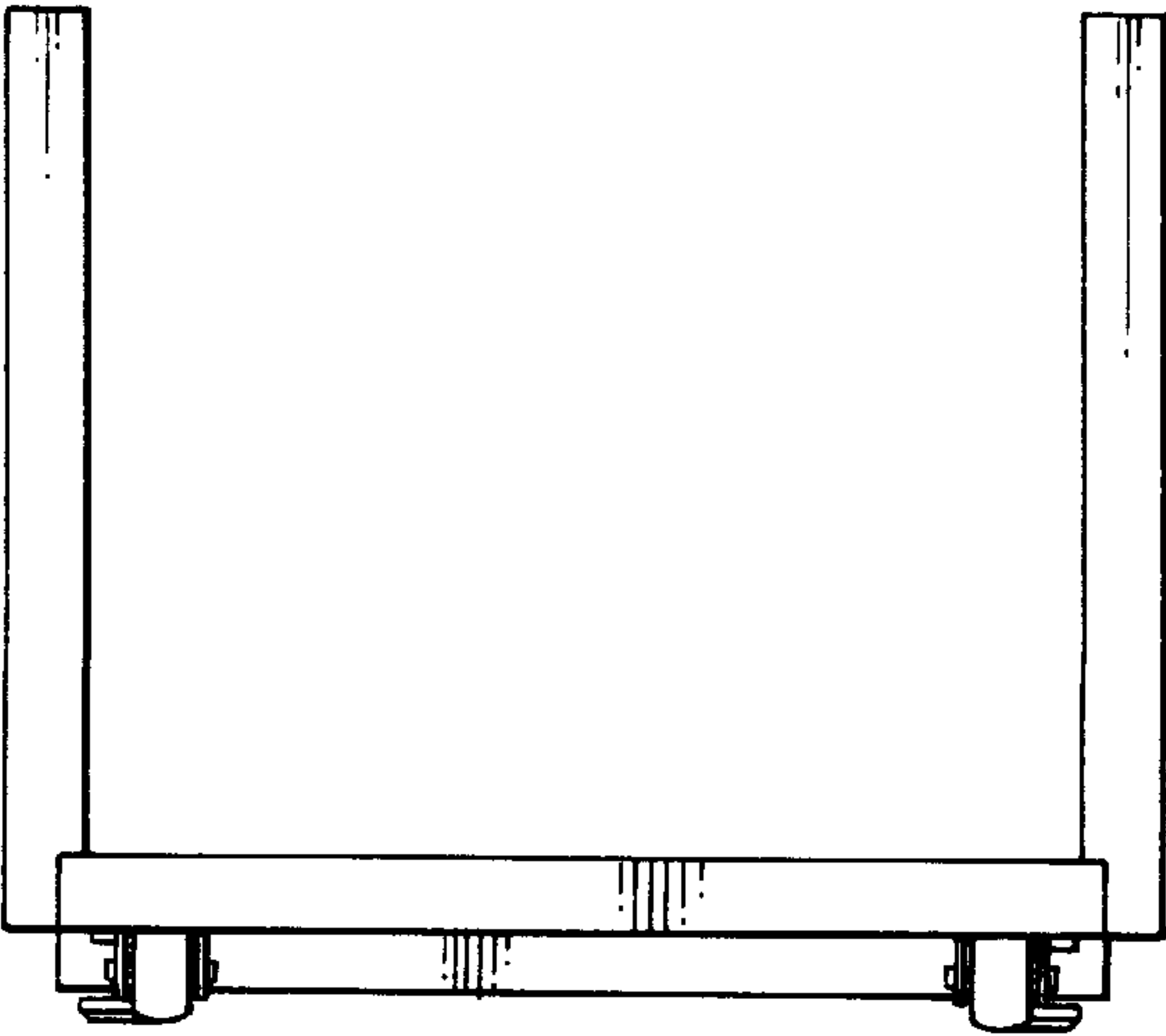


FIG. 11

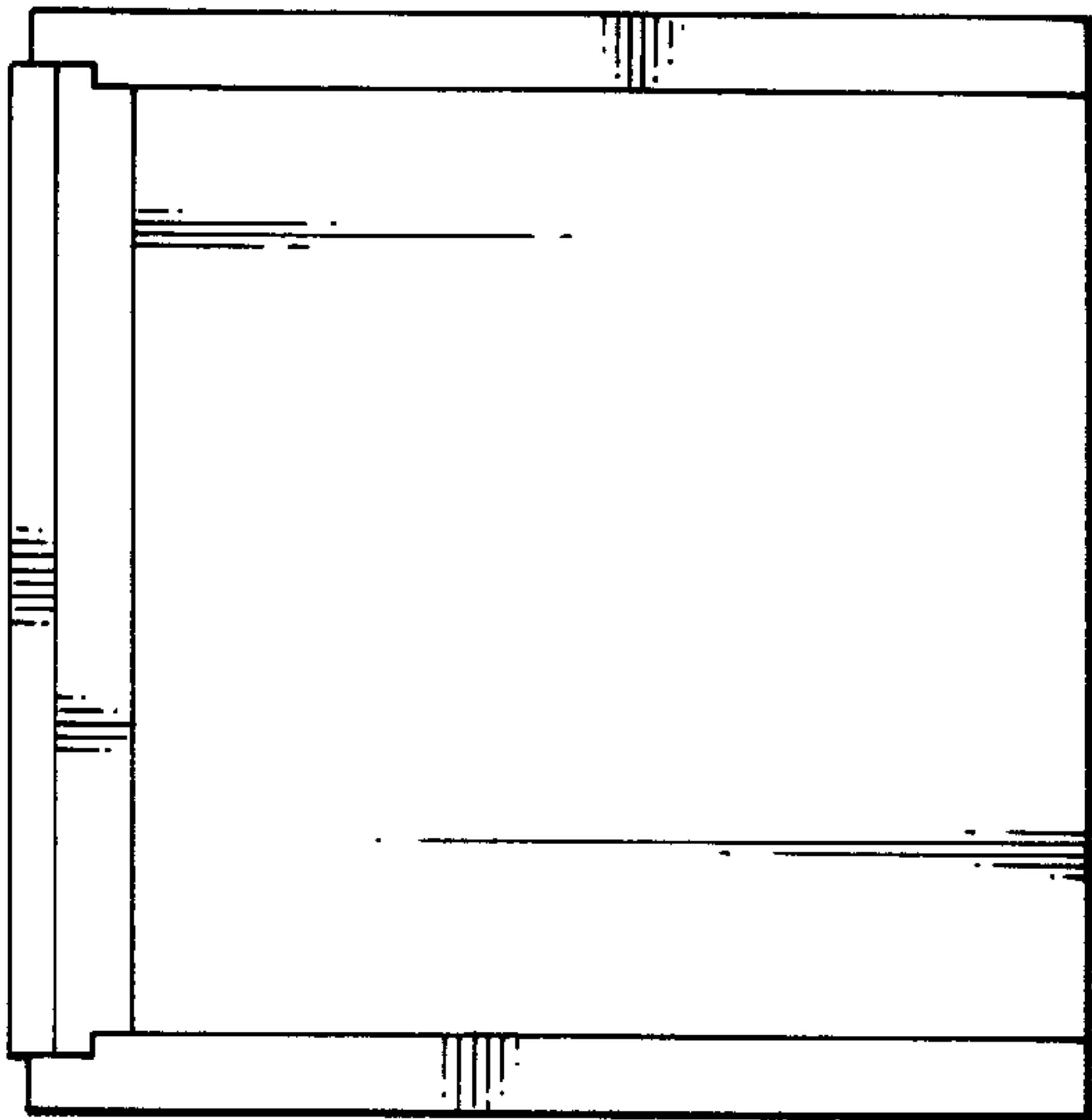


FIG. 12

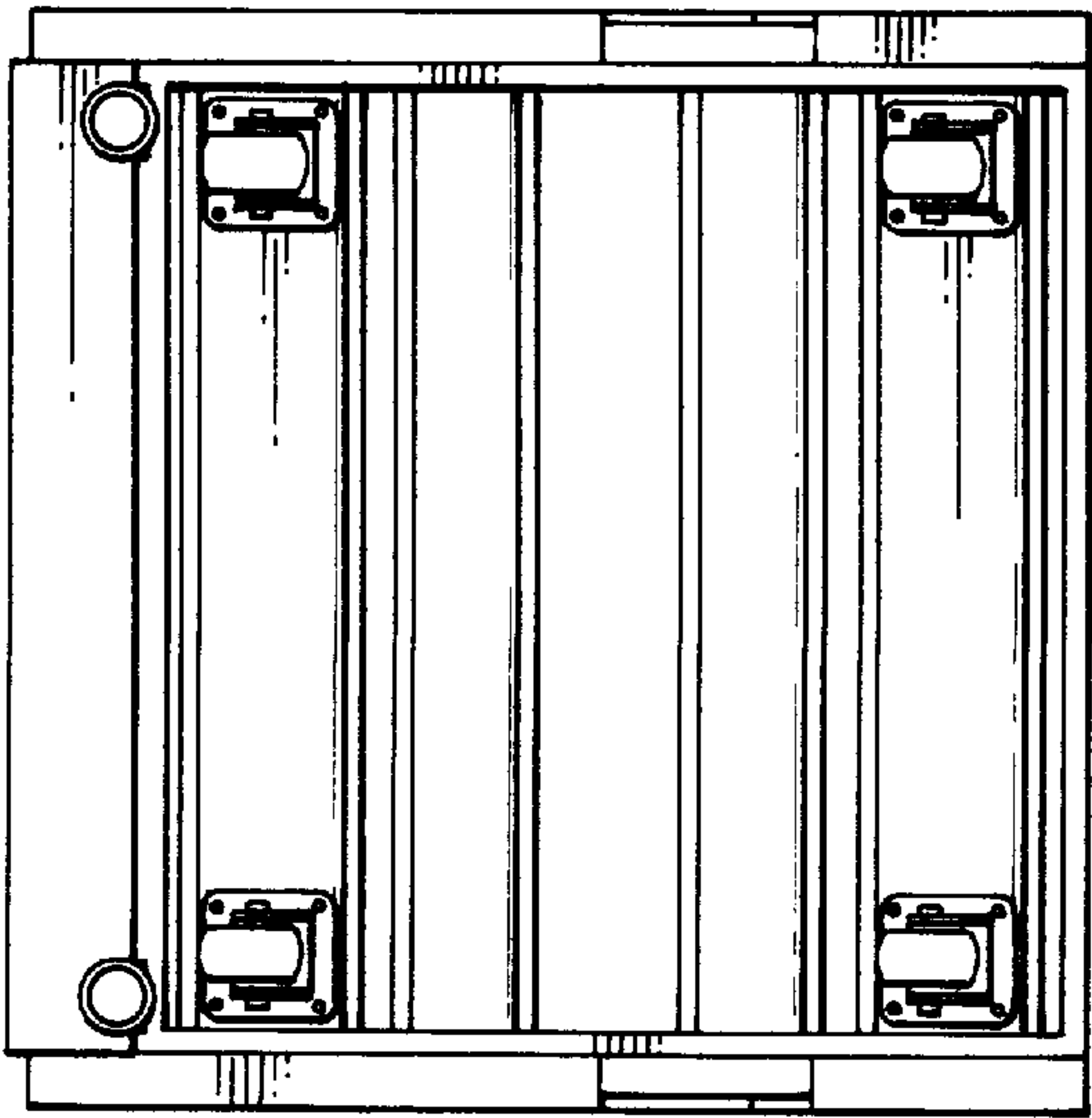


FIG. 13

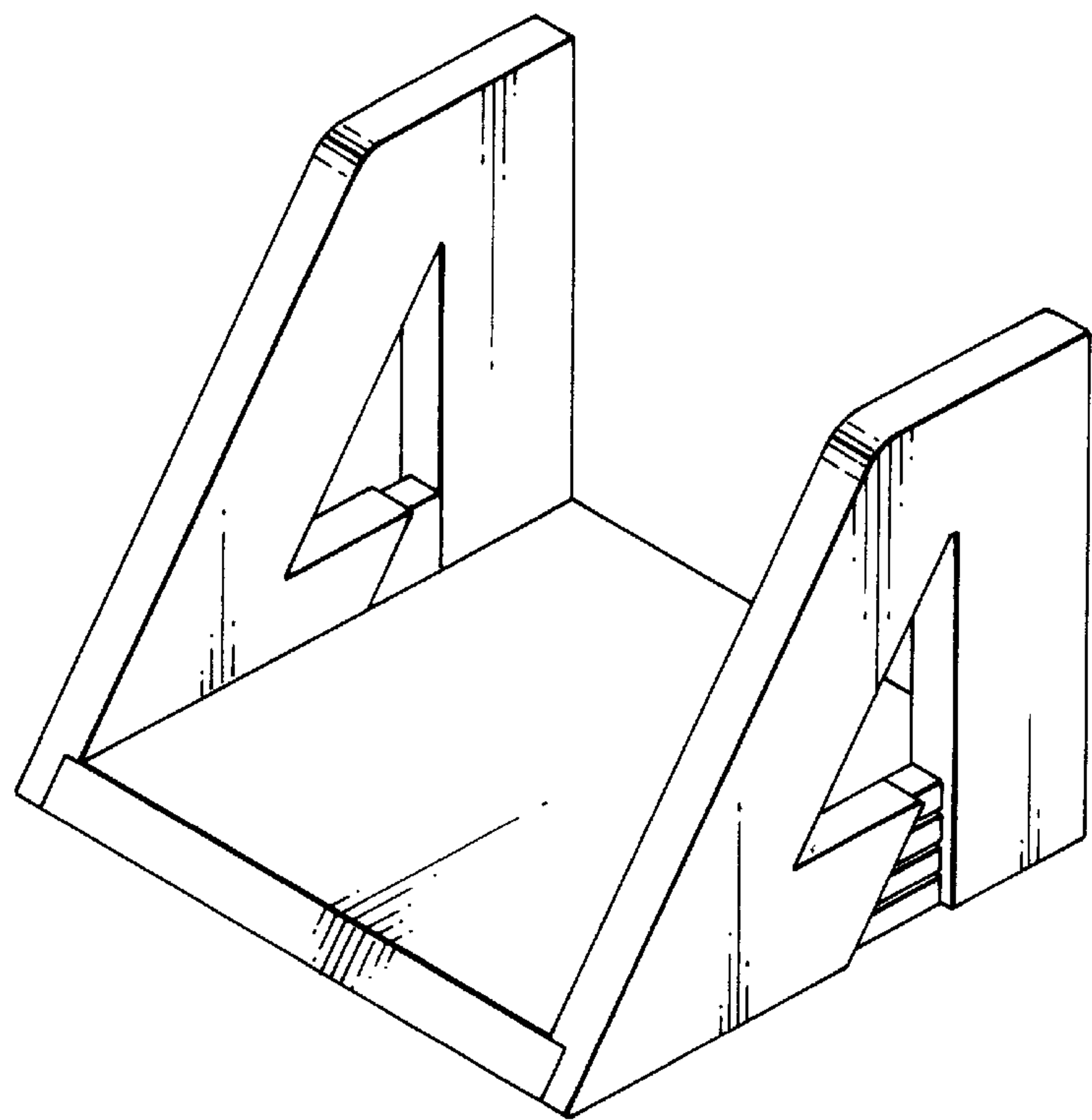


FIG. 14

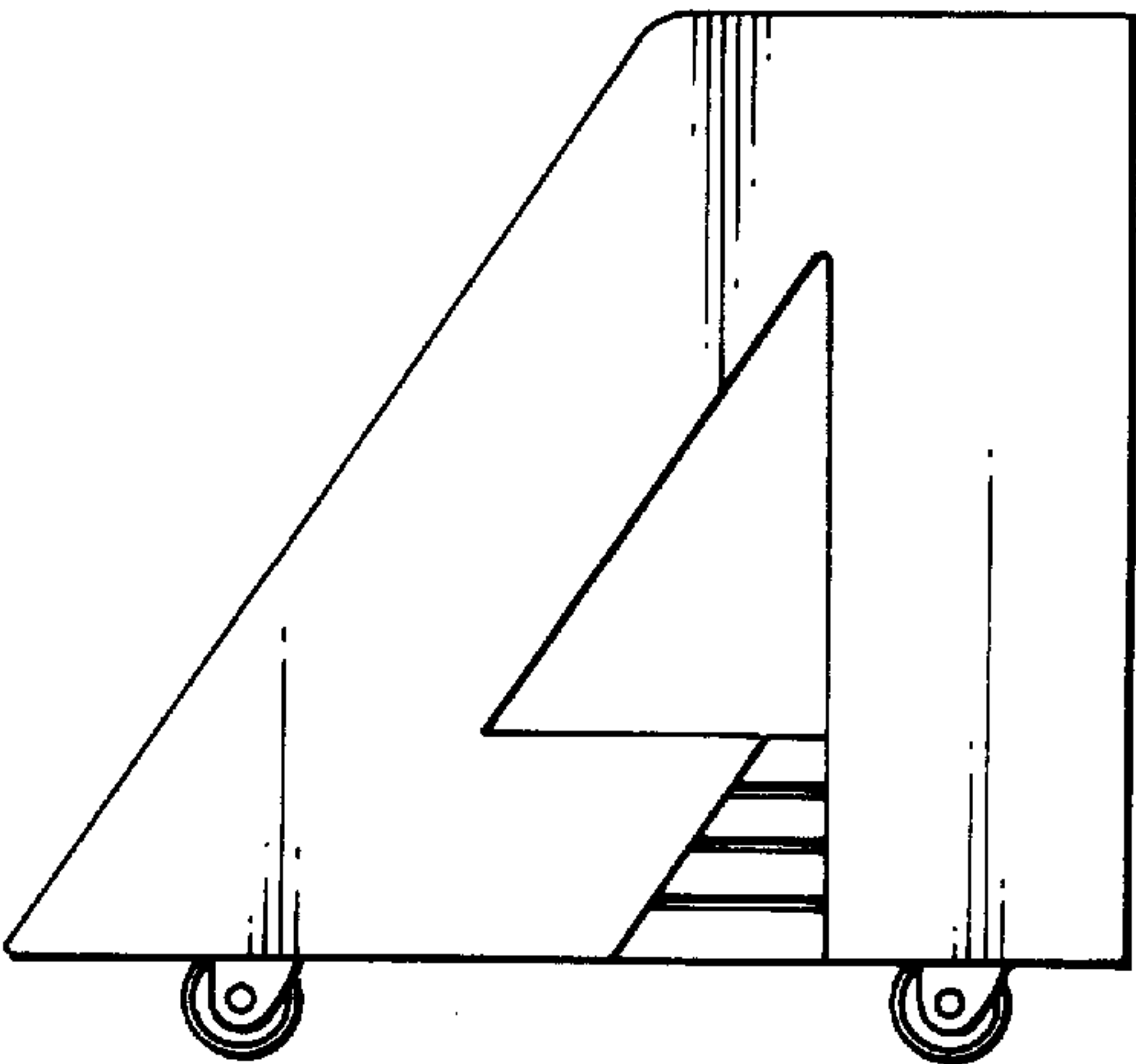




FIG. 15

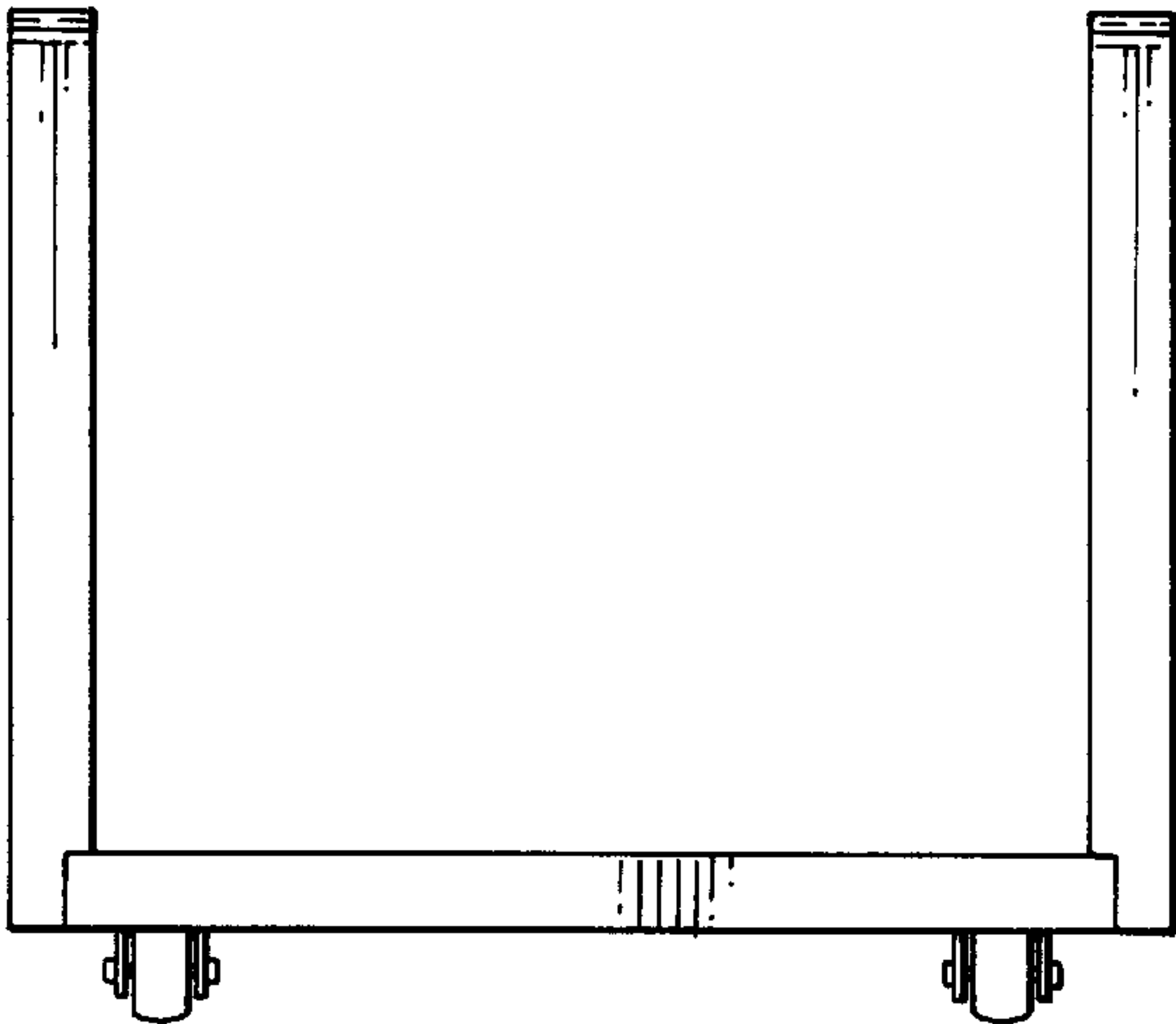


FIG. 16

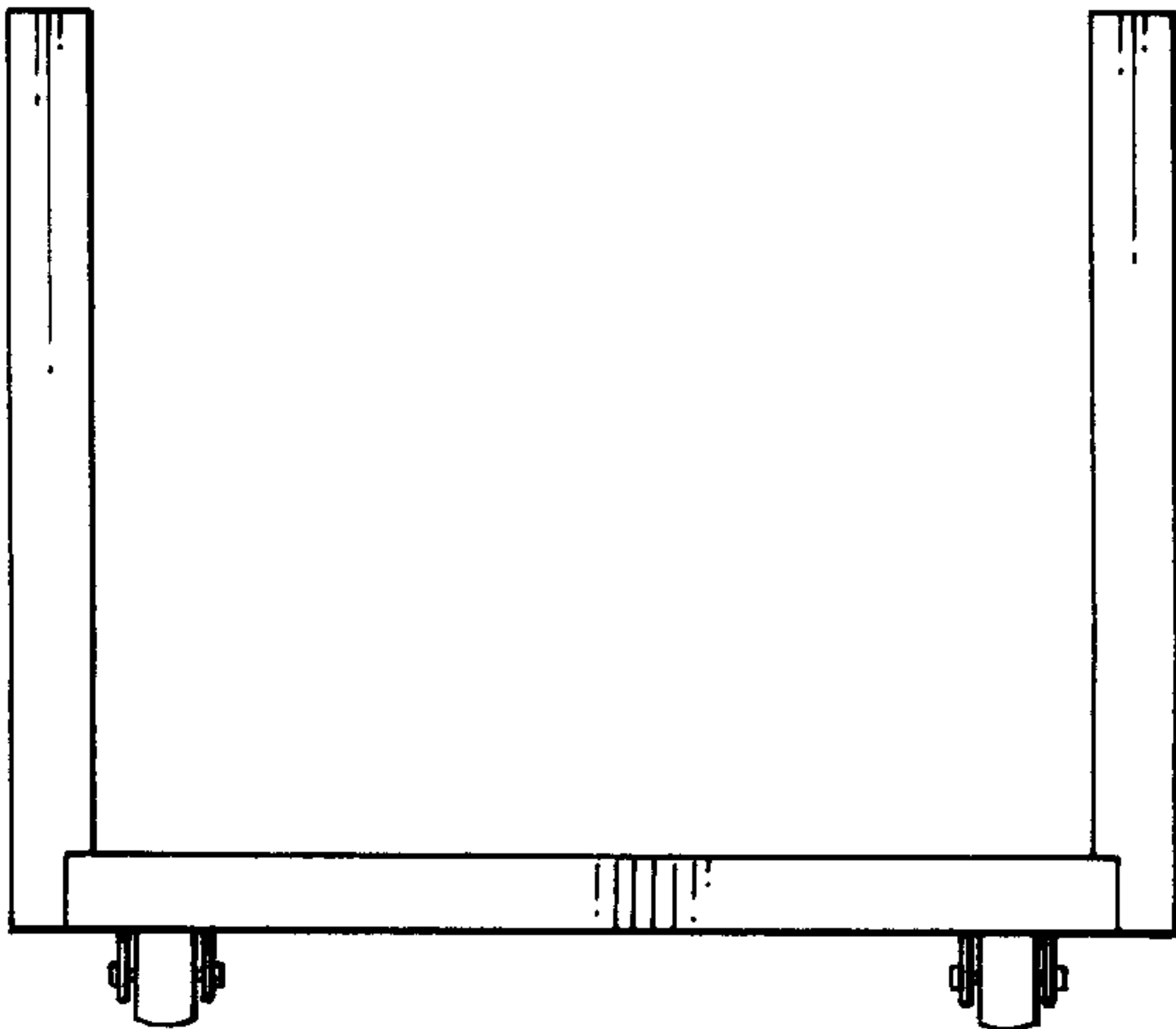


FIG. 17

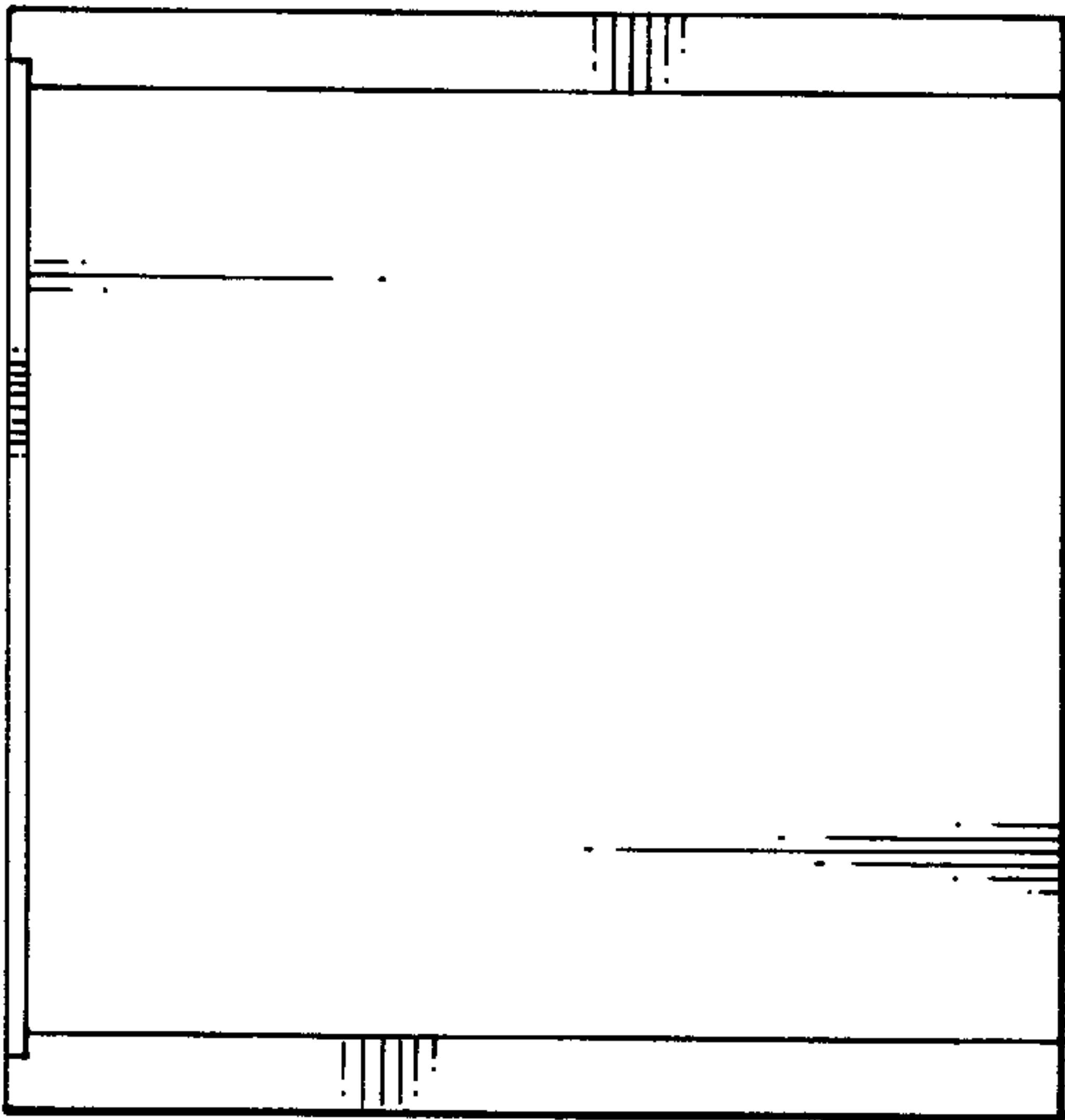


FIG. 18

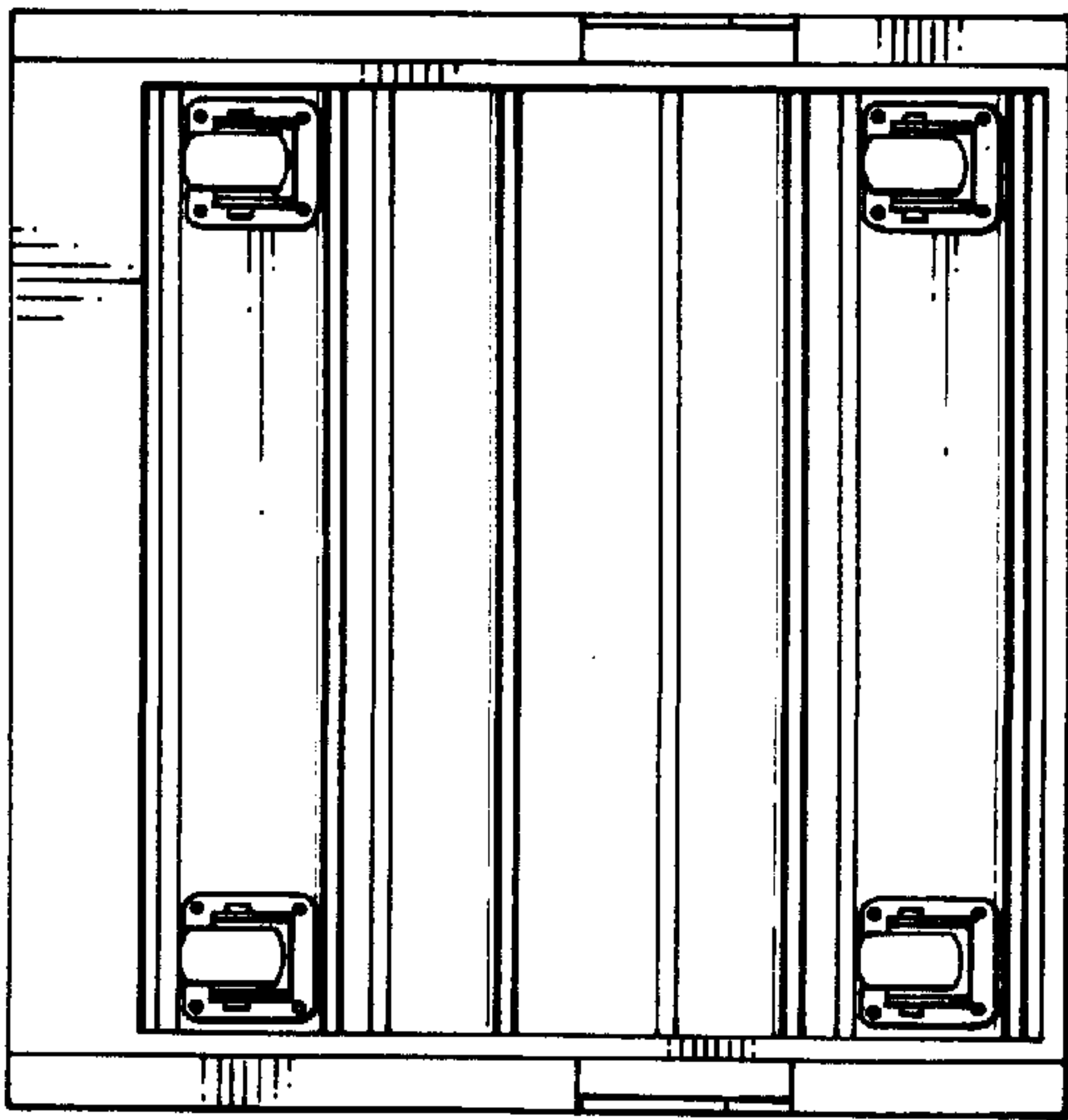
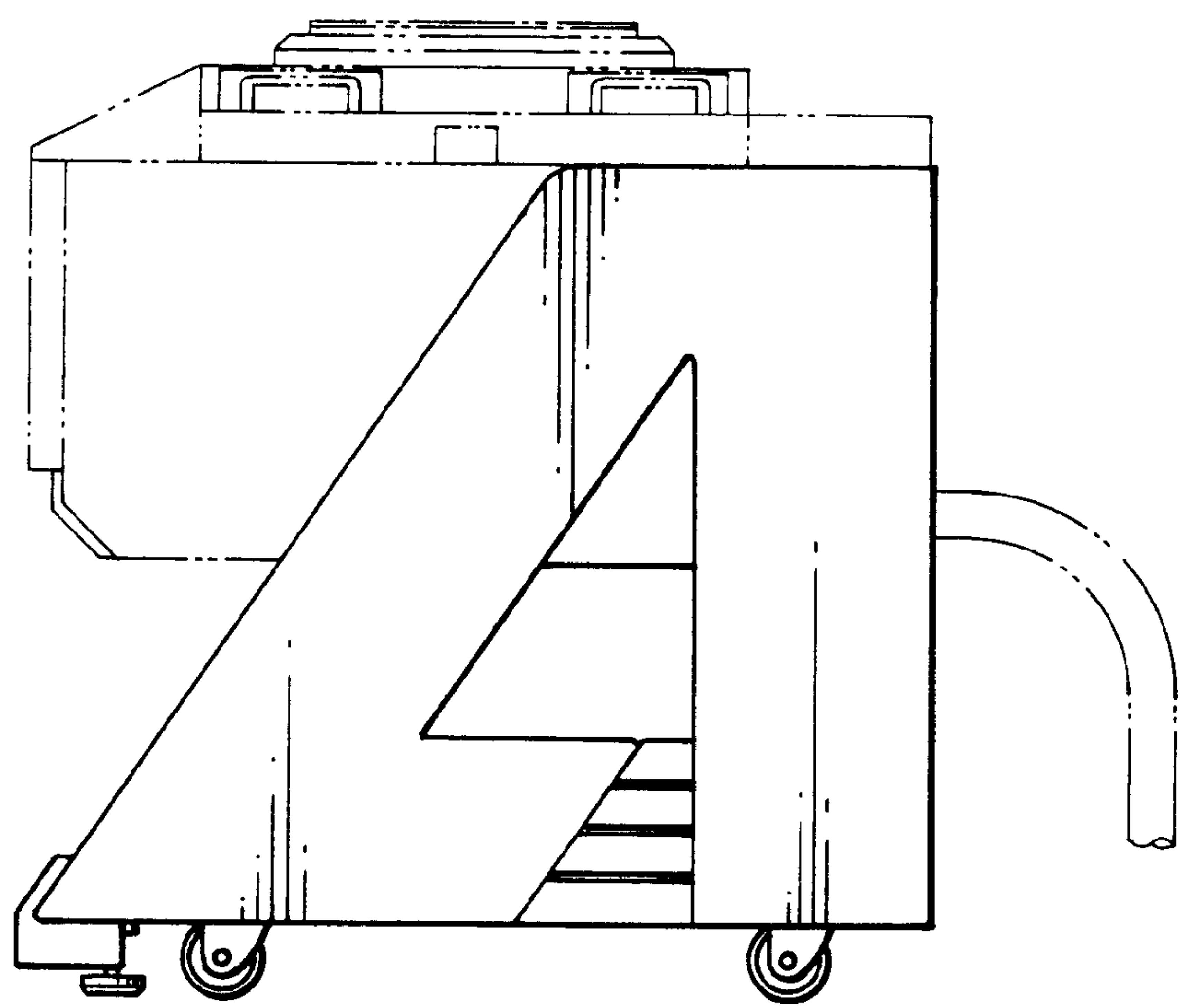


FIG. 19



UNITED STATES PATENT AND TRADEMARK OFFICE  
**CERTIFICATE OF CORRECTION**

PATENT NO. :Des 420,927  
DATED :February 22, 2000  
INVENTOR(S) :Takayuki Yano

Page 1 of 1

It is certified that error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

Title Page:

Insert the following Priority Data :

"JAPAN 10-19566 July 7, 1998; JAPAN 10-19567 JULY 7, 1998, and JAPAN 10-19568 JULY 7, 1998".

Signed and Sealed this

Seventeenth Day of July, 2001

Attest:

*Nicholas P. Godici*

NICHOLAS P. GODICI

Attesting Officer

Acting Director of the United States Patent and Trademark Office

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DATED : February 22, 2000  
INVENTOR(S) : Takayuki Yano

Page 1 of 1

It is certified that error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:


Title page,  
Insert Item:

-- [30]            **Foreign Application Priority Data**

JAPAN	10-19566	July 7, 1998;
JAPAN	10-19567	July 7, 1998; and
JAPAN	10-19568	July 7, 1998 --.

Signed and Sealed this

Seventh Day of December, 2004

A handwritten signature in black ink on a light gray dotted background. The signature reads "Jon W. Dudas" in a cursive, stylized script. The "J" is large and loops around the "on". The "W" is formed by two connected 'u' shapes. The "D" is a large, open loop, and "udas" follows in a similar cursive style.

JON W. DUDAS

*Director of the United States Patent and Trademark Office*